



EV832832850

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. 10/705,685
Confirmation No. 4637
Filing Date November 10, 2003
Inventors John R. Tuttle
Assignee Micron Technology, Inc.
Group Art Unit 2612
Examiner Tai T. Nguyen
Customer No. 021567
Attorney Docket No. MI40-382
Title: Thin, Flexible, RFID Label and System for Use (as amended)

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References – See Attached Form PTO-1449


In compliance with 37 C.F.R. §§1.56, 1.97 and 1.98, your attention is directed to the United States patents listed on the attached Form PTO-1449. No admission is made regarding whether the submitted references are prior art.

Citation of these references is respectfully requested.

This Supplemental Information Disclosure Statement is being filed with a Request for Continued Examination (RCE). Therefore, no fee is believed to be required. However, in the event that a fee is required for filing this Supplemental Information Disclosure Statement, please charge the fee specified under 37 C.F.R. §1.17(p) to Deposit Account No. 23-0925.

Respectfully submitted,

Dated: Sept, 12, 2006

By: 
Deepak Malhotra
Reg. No. 33,560

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Form PTO-1449				ATTY. DOCKET NO. MI40-382		SERIAL NO. 10/705,685					
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				APPLICANT JOHN R. TUTTLE							
<div style="position: relative; height: 100px;"> <div style="position: absolute; top: 0; left: 0; width: 100%; height: 100%; border: 1px solid black; border-radius: 50%; text-align: center; line-height: 100px; font-size: 20px; font-weight: bold;"> OFFICE SEP 12 2006 PATENT AND TRADEMARK OFFICE </div> </div>				LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				FILING DATE NOV. 10, 2003		GROUP 2612	
U.S. PATENT DOCUMENTS											
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate				
	AA	4,413,254	11/01/83	PINNEO ET AL.	340	572					
	AB	4,506,148	03/19/85	BERTHOLD ET AL.	235	380					
	AC										
	AD										
	AE										
	AF										
	AG										
FOREIGN PATENT DOCUMENTS											
		Document Number	Date	Country	Class	Subclass	Translation				
							Yes	No			
	AH										
	AJ										
	AK										
	AL										
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)											
	AM										
	AN										
	AO										
	AP										
EXAMINER		DATE CONSIDERED									
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>											